Supplementary Information

Stretchable and Skin-conformable Conductors Based on Polyurethane/Laser-Induced Graphene

*Alexander Dallinger^a , Kirill Keller^a , Harald Fitzekb,c, Francesco Grecoa,**

a Institute of Solid State Physics, NAWI Graz, Graz University of Technology, Petersgasse 16, 8010 Graz, Austria.

b Graz Centre for Electron Microscopy (ZFE), Steyrergasse 17, 8010 Graz, Austria

c Institute for Electron Microscopy and Nanoanalysis (FELMI), NAWI Graz, Graz University of Technology, Steyrergasse 17, 8010 Graz, Austria

* Corresponding author, email: francesco.greco@tugraz.at

Figure S1. Schematics of MPU layers.

Figure S2. Force curves for MPU samples for 5%, 10%, 30% and 100% strain cycles repeated five times.

Table S1. Summary of properties of MPU.

Property	Value
Thickness	$54\pm6 \text{ }\mu\text{m}$
Young's Modulus	$(8.5 \pm 0.3)MPa$
Elongation at break	$>400\%$
WVTR ¹	564-648 g/m ² /24 h

¹ Water Vapor Transmission Rate (WVTR) provided by BSN medical.

Table S2. Summary of Raman spectra band parameters.

Figure S3. Map of LIG formation on PI influenced by laser power and speed parameters, resulting in different fluence H.

Figure S4. Stretching curve for LIG-P/MPU sample with a 100% strain/relaxation cycle and corresponding variation of electrical resistance, showing a reversible breakdown at around 60% strain (plot cut off at 1000 k Ω for better visibility).

Figure S5. Stretching curve for LIG-F/MPU sample with a 100% strain/relaxation cycle and corresponding variation of electrical resistance, showing no breakdown during the full cycle.

Figure S6. Stress relaxation curve from an applied 30% tensile strain on LIG-P/MPU, as used in fitting for the relaxation time constant for the I and II relaxations.

Figure S7. Fitting of (a) force and (b) resistance of I relaxation in Figure S6 and fitting of (c) resistance of II relaxation in Figure S6 with two exponential functions $(a \cdot e)$ $-\mathcal{X}$ $\tau_1 + b \cdot e$ $-\mathcal{X}$ $\overline{\tau_2}$), resulting in a time constant $\tau_1 = 18.5 \pm 2.8$ s and $\tau_2 = 3100 \pm 1400$ s.

Figure S8. Starting resistance R_0 before each strain cycle for all LIG/MPU types.

Figure S9. Change of maximum resistance R_{max} and relaxed resistance R_{relax} over 200 cycles of tensile testing at 30% strain in the case of a) LIG-F \perp /MPU (ϕ = 90°), b) LIG-F \parallel /MPU (ϕ = 0°), c) LIG-P \perp /MPU ($\phi = 90^\circ$) and d) LIG-P \parallel /MPU ($\phi = 0^\circ$).

Figure S10. Force curve of MPU sample with a strain cycle of 30% imposed 200 times extracted from Figure S9.

Figure S11. Fitting of Young's Modulus ($Y = 8.5 \pm 0.3$ MPa) for LIG-F/MPU with 30% strain.

Figure S12. Fitting of Young's Modulus ($Y = 8.5 \pm 0.3$ MPa) for MPU with 30% strain.

Figure S13. Custom tensile testing setup for mechanical and electrical characterization showing (A) load cell, (B) electrical contacts, (C) sample, (D) movable stage.

Calculation of laser fluence

The laser fluence *H* for each laser raster setting was calculated as

$$
H = \frac{P \cdot P_{max} / 100}{s \cdot v \cdot PPI} \tag{S1}
$$

where *P* is the set laser power (%) with respect to the maximal laser power $P_{max} = 30 \text{ W}$, *s* is the theoretical laser spot size determined according to gaussian beam theory, *v* is the measured processing speed (depending on the sample size, $v \sim 110 \pm 10$ mm/s) and PPI the raster resolution.